## Search Notes



Application/Control No.	Applicant(s)/Patent unde Reexamination	Applicant(s)/Patent under Reexamination	
10/601,499	NAVADA ET AL.		
Examiner	Art Unit		
Harold Kim	2182		

SEARCHED					
Class	Subclass	Date	Examiner		
710	53, 52, 56, 57	11/13/2005	нк		
711	154, 155	11/21/2005	нк		
711	165, 109	11/21/2005	нк		

INTERFERENCE SEARCHED					
Class	Subclass	Date	Examiner		
710	53, 52	11/13/2005	нк		
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SEARCH NOTES (INCLUDING SEARCH STRATEGY)				
	DATE	EXMR		
USPAT, USPGPUB, JPO, EPO, IEEE, NPL, PLUS, see attached search note, inventor search on eDan	11/13/2005	нк		
Search consulted with Primary Chris Shin, and Ilwoo Park in AU2182 and Primary Hong Kim in AU2185	11/21/2005	нк		

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And 6: 1/20/05